

Search Notes

Application/Control No.

10/710,383

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under
Reexamination

YAMADA, TAKASHI

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	194	6/7/2005	HN
310	71	6/7/2005	HN
310	258	6/7/2005	HN
310	259	6/7/2005	HN
310	316	6/7/2005	HN
310	217	6/7/2005	HN
310	218	6/7/2005	HN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consult Dang Le, Primary Examiner for allowance	6/7/05	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner